## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10563617	NAKAMURA, NAOHITO
Examiner	Art Unit
M. Lee	2622

SEARCHED				
Class	Subclass	Date	Examiner	
348	725, 726, 731, 732, 733	3/23/09	ml	
375	329, 279, 326, 332, 224-226, 346, 338,	3/23/09	ml	
455	226.1-226.4	3/23/09	ml	
370	333, 332, 334	3/23/09	ml	
714	49, 704	3/23/09	ml	

SEARCH NOTES		
Search Notes	Date	Examiner
east	3/23/09	ml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examine
	Interference search history attached.	3/23/09	ml

/M. Lee/ Primary Examiner.Art Unit 2622

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